

# Product data sheet

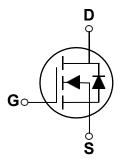
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SOT-23



#### **Features**

- 30V, 2.0 A,  $RDS(ON) = 300m\Omega@VGS = 4.5V$
- *Improved dv/dt capability*
- Fast switching
- Green Device Available

#### Applications

- Notebook
- Load Switch
- LED applications

BVDSS	RDSON	ID
30V	$300 \text{m}\Omega$	2.0A

#### Absolute Maximum Ratings Tc=25°C unless otherwise noted

Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	30	V
Vgs	Gate-Source Voltage	±12	V
1	Drain Current – Continuous (T <sub>C</sub> =25°C)	2.0	A
Drain Current – Continuous (Tc=100°C)		1.2	A
l <sub>DM</sub>	Drain Current – Pulsed <sup>1</sup>	4.0	A
D	Power Dissipation (Tc=25°C)	1.0	W
Po	Power Dissipation – Derate above 25°C	0.012	W/°C
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

#### **Thermal Characteristics**

Symbol	Parameter	Тур.	Max.	Unit
R <sub>0JA</sub> Thermal Resistance Junction to ambient			80	°C/W



## Electrical Characteristics (TJ=25 °C, unless otherwise noted)

#### **Off Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	30			V
$\triangle BV_{DSS}   \triangle T_J$	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25℃ , I <sub>D</sub> =1mA		0.06		V/°C
	Drain Course Lookers Current	V <sub>DS</sub> =30V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1	uA
IDSS Drain-Source Leakage Current	Drain-Source Leakage Current	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =125°C			10	uA
lgss	Gate-Source Leakage Current	$V_{GS}=\pm 12V$ , $V_{DS}=0V$			±100	nA

#### **On Characteristics**

Proven	Static Drain-Source On-Resistance	V <sub>GS</sub> =4.5V , I <sub>D</sub> =2A		200	400	- m0	
R <sub>DS(ON)</sub> Static Drain-Source On-Resistance		V <sub>GS</sub> =2.5V , I <sub>D</sub> =1A		400	600	mΩ	
V <sub>GS(th)</sub>	Gate Threshold Voltage			0.8	1.2	V	
$\bigtriangleup V_{GS(th)}$	V <sub>GS</sub> (th) Temperature Coefficient			-3		mV/°C	
gfs	gfs Forward Transconductance V <sub>DS</sub> =10V , I <sub>S</sub> =3A			7		S	

#### **Dynamic and switching Characteristics**

Qg	Total Gate Charge <sup>2,3</sup>			8.4	
Qgs	Gate-Source Charge <sup>2,3</sup>	$V_{DS}$ =10V , $V_{GS}$ =4.5V , $I_{D}$ =1A		1	 nC
Q <sub>gd</sub>	Gate-Drain Charge <sup>2,3</sup>			2.2	
T <sub>d(on)</sub>	Turn-On Delay Time <sup>2,3</sup>			4.5	
Tr	Rise Time <sup>2,3</sup>	$V_{DD}$ =10V , $V_{GS}$ =4.5V , $R_{G}$ =25 $\Omega$		13	 
T <sub>d(off)</sub>	Turn-Off Delay Time <sup>2,3</sup>	I <sub>D</sub> =1A		27	 nS
Tf	Fall Time <sup>2,3</sup>			8.3	
Ciss	Input Capacitance			695	
Coss	Coss Output Capacitance VDs=10V , VG			45	 pF
Crss	Reverse Transfer Capacitance			36	 ]
Rg	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, F=1MHz		1.5	 Ω

Drain-Source Diode Characteristics and Maximum Ratings						
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			2.0	А
lsм	Pulsed Source Current				4.0	А
Vsd	Diode Forward Voltage	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25℃			1.2	V

Note :

1. Repetitive Rating : Pulsed width limited by maximum junction temperature.

2. The data tested by pulsed , pulse width  $\leq 300 us$  , duty cycle  $\leq 2\%.$ 

3. Essentially independent of operating temperature.



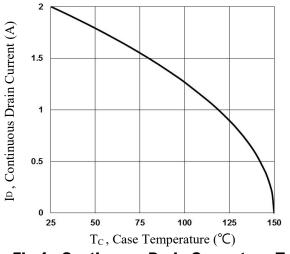
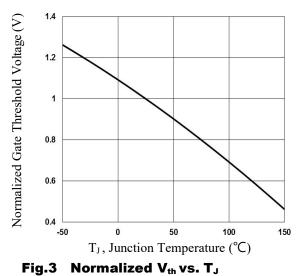


Fig.1 Continuous Drain Current vs. Tc



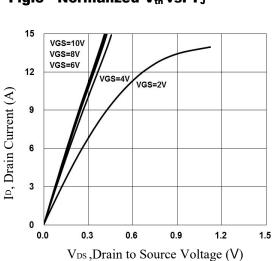
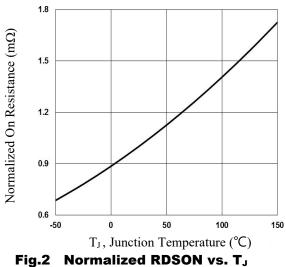


Fig.5 Typical Output Characteristics



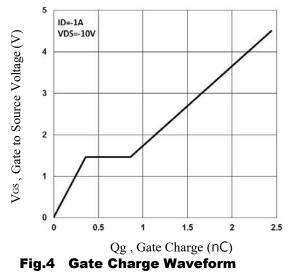
FDV303N

Semiconductor

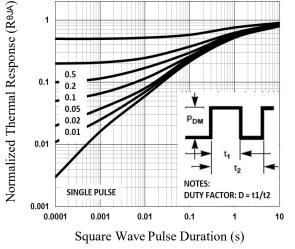
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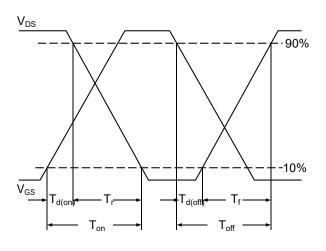
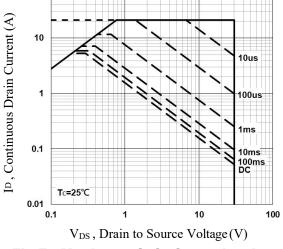


Fig.8 Switching Time Waveform



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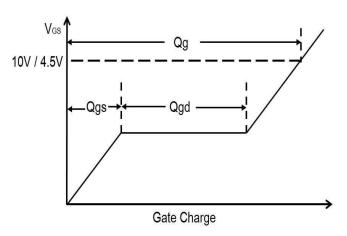
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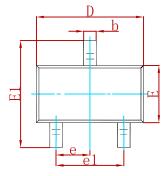


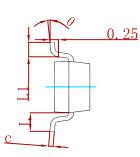


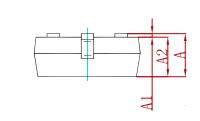




## PACKAGE MECHANICAL DATA

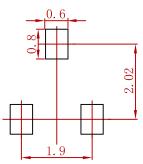






Symbol	Dimensions	Dimensions In Millimeters		s in inches
Symbol	Min	Max	Min	Max
А	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
С	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
E	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
е	0.950	) TYP	0.037	7 TYP
e1	1.800	2.000	0.071	0.079
L	0.550 REF		0.022	REF
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

## Suggested Pad Layout



Note:

Controlling dimension:in millimeters.
General tolerance:± 0.05mm.
The pad layout is for reference purposes only.

## **REEL SPECIFICATION**

P/N	PKG	QTY
FDV303N	SOT-23	3000





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